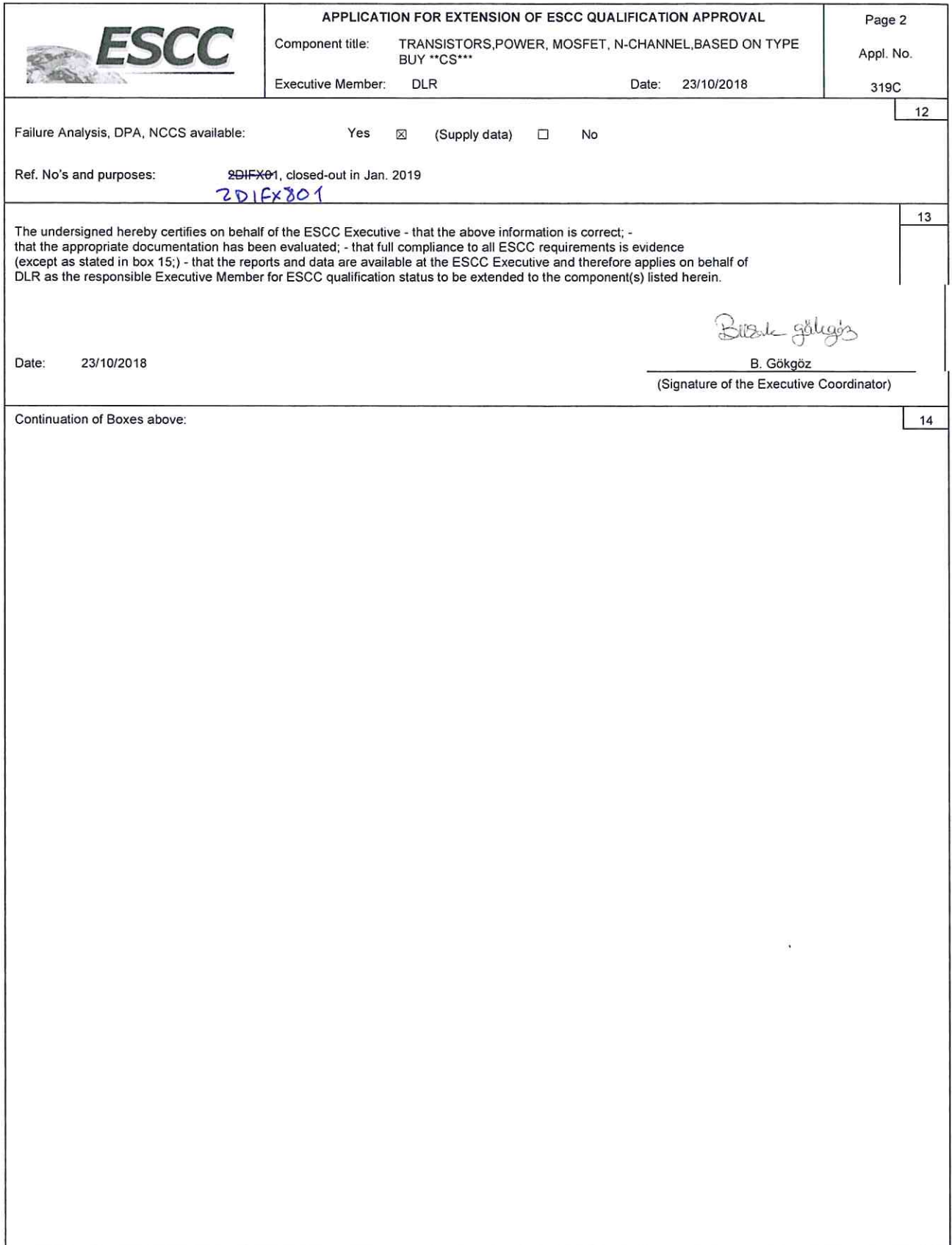


		APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL				Page 1 Appl. No.
		Component Title: TRANSISTORS, POWER, MOSFET, N-CHANNEL, BASED ON TYPE BUY **CS***				319C
		Executive Member: DLR		Date: 23/10/2018		
Components (including series and families) submitted for Extension of Qualification Approval:						1
ESCC COMPONENT NO.	VARIANTS	RANGE OF COMPONENTS	BASED ON	TEST VEHICLE / S	COMPONENT SIMILAR	
5205/026	01R		BUY25CS12J01			
5205/027	01R		BUY25CS54A01	BUY25CS45B-01(ES)		
5205/028	01R		BUY10CS12J01	BUY25CS12J-01(ES)		
5205/030	01R, 02R and 03R		BUY25CS12K01 BUY25CS45B01			
Component Manufacturer Infineon Technologies AG		Location of Manufacturing Plant(s) Am Campeon 1-12 D- 85579 Neubiberg Germany		Date of original qualification approval: Date: 28/09/2012 Certificate Ref No. 319		4
ESCC Specifications used for Maintenance of qualification testing: Generic: 5010 Issue: 03 Detail(s): 5205/030 Issue: 01 5205/026 Issue: 02		Deviations to LVT testing and Detail Specification used: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (supply details in Box 15) Deviation from current Specifications: No <input checked="" type="checkbox"/> Yes <input type="checkbox"/> (Supply details)		Qualification Extension Report reference and date: 1808LR20, Issue: Iss. 1, Jun 2018 1808LR23, Issue: Iss. 1, Jun 2018		7
Summary of procurement or equivalent test results during current validity period in support of this application (those to ESCC listed first)						8
Project Name	Testing Level	LAT	Date code	Quantity Delivered		
PID changes since last MoQ None <input type="checkbox"/> Minor* <input checked="" type="checkbox"/> Major* <input type="checkbox"/> *Provide details in box:		Current PID Verified by: B. Gökgöz Name of Executive Representative Ref No: Generic PID: A63500-GEPIID-P000, Issue 2c, 18.10.2018 Detail PID: A63500-L5491-P000, Issue 7a, 18.10.2018 Issue: See above Date: See above Rev Date: 26/10/2018				10
See Detail PID						
Current Manufacturing facilities surveyed by:		T. Kaupisch and B. Gökgöz, DLR; L. Bonora and F. Martinez, ESA (Name of Executive Representative)		on 17-18/10/2018 (Date)		11
Satisfactory: Yes <input checked="" type="checkbox"/> No <input type="checkbox"/> Explain						
Report Reference: IFX-AUD-2018						



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		Component title: TRANSISTORS, POWER, MOSFET, N-CHANNEL, BASED ON TYPE BUY **CS**		
		Executive Member: DLR		Date: 23/10/2018
Non compliance to ESCC requirements:				15
No.:	Specification	Paragraph	Non compliance	
1	ESCC 5000 iss 7 (July 2017)		issue 6 used for this maintenance of qualification	
Additional tasks required to achieve full compliance for ESCC qualification or rationale for acceptability of noncompliance:				
1. A revised update of PID has been approved in October 2018.				
Executive Manager Disposition				
Application Approval: Yes <input checked="" type="checkbox"/> No <input type="checkbox"/>				
Action / Remarks:				
Date: 31.1.2019				
 Signature ESA: B. Schade, Head of Product Assurance and Safety Department				



APPLICATION FOR EXTENSION OF ESCC QUALIFICATION APPROVAL

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ANNEX 1: LIST OF TESTS DONE TO SUPPORT EXTENSION OF QUALIFICATION

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Tests conducted in compliance with:

- ESCC 5010 generic specification; Chart V (for ESCC/QPL parts);

Tests vehicle identification/description:

1808LR20	BUY25CS45B-01(ES), EndSG, AssCapSG f. TO packages, 1747B
1808LR23	BUY25CS12J-01(ES), EnvMechSG f. SMD packages, 1748C

Detail Specification reference: 5205/026 and 5205/030

Chart F4A	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Environmental/Mechanical Subgroups	Shock Test	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2016	1748C	18	0	
	Vibration Test	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2056	1748C	18	0	
	Constant Acceleration	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2006	1748C	18	0	
	Seal Test (Fine and Gross Leak)	<input checked="" type="checkbox"/>	MIL-STD-883, Test Method 1014, Test Condition A1 or A2	1748C	18	0	acc. Detail Spec
	Electrical Measurements at Room Temp.	<input checked="" type="checkbox"/>	Table 2 of the Detail Specification	1748C	18	0	
	External Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20500	1748C	18	0	
	Temperature Cycling	<input checked="" type="checkbox"/>	MIL-STD-883 Test Method 1010, Test Condition C, 20 cycles	1748C	18	0	acc. Detail Spec
	Moisture Resistance	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 1021	1748C	18	0	
	Seal Test (Fine and Gross Leak)	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 1071	1748C	18	0	
	Electrical Measurements at Room Temp.	<input checked="" type="checkbox"/>	Table 2 of the Detail Specification	1748C	18	0	
	External Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20500	1748C	18	0	
Endurance Subgroup	Operating Life	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 1026	1747B	16	0	
	Electrical Measurements during Endur. Test	<input checked="" type="checkbox"/>	Table 6 of the Detail Specification	1747B	16	0	
	External Visual Inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20500	1747B	16	0	



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Chart F4A	Test	Tick when done	Conditions	Date Code Diffusion Lot	Tested Qty	No. of Rejects	Comments if not performed. Comments on Rejection
Assembly Capability Tests	Solderability Test	<input type="checkbox"/>	MIL-STD-750 Test Method 2026				n.a. acc. Detail Spec
	Permanence of Marking	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 24800	1747B	6	0	
	Terminal Strength	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2036	1747B	6	0	
De- encapsulation Tests	Internal visual inspection	<input checked="" type="checkbox"/>	ESCC Basic Specification No. 20400	1747B	6	0	
	Bond Strength	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2037	1747B	6	0	
	Die Shear	<input checked="" type="checkbox"/>	MIL-STD-750 Test Method 2017	1747B	6	0	

